

WELCOME TO APMC- 2020

Venue: Hyderabad International Convention Centre, Hyderabad.

Date: 3rd -7th February 2020

INVITATION FOR JEOL INSTRUMENT DEMO

JEOL continues to evolve.....

71st years since our founding in 1949.

We welcome all the participants at APMC-2020 for live demo and hands on experience on our latest products line. We believe that you will be a delightfully surprised to see our latest innovations in both concept and the design as well as talking to our experts.

Features:

- ☞ "Zeromag" function, sample navigation is even easier than ever before.
- ☞ SEM image on surface details, enables you to quickly locate areas for imaging and analysis.
- ☞ It shows a real time EDS spectrum during image observation for quick and efficient elemental analysis.
- ☞ "Live 3D" function enables simultaneous observation of a live SEM image.

JCM-7000 Benchtop Scanning Electron Microscope



JSM-7900F Field Emission SEM with EDS and EBSD



JSM-7900F is JEOL's new flagship FE-SEM which combines extreme high resolution imaging, enhanced stability.

Features:

- ☞ Improvement of automation function
- ☞ Improvement of Magnification accuracy
- ☞ GBSH-S(GENTLEBEAM™ Super High resolution Stage bias mode)
- ☞ New Backscattered Electron Detector
- ☞ New Sample Exchange method

JEOL will be happy to arrange a demonstration for you. **So hurry up and book your slot early for live demo at our booth.**

Please register your name for demonstration:
info@jeolindia.com (011-45958000)

We will look forward to see you soon at APMC-Hyderabad.